


<b>Search Notes</b>  	<b>Application/Control No.</b>  10589143	<b>Applicant(s)/Patent Under Reexamination</b>  DEMENTIEVA ET AL.
	<b>Examiner</b>  JaNa Hines	<b>Art Unit</b>  1645

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SEARCH NOTES		
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STIC search, inventor search, related apps, commercial databases, west cluster, biotech cluster, epo, japio, wpids, caplus, hcplus, derwent, STN/CAS files, text word search comprising claim language words,	2/2009	JAH

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